

# Confocal Raman Microscopy and Neutron Reflectometry Profiling of Composition at Polymer-Polymer Interfaces



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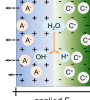
## 1. Overall Objectives:

- Adapt **confocal Raman microscopy**<sup>1</sup> for spatial profiling ion composition across the **AEM-CEM (anion-exchange membrane / cation-exchange membrane) interface within bipolar polymer membranes**.
- Develop a platform to perform **neutron reflectometry (NR)**<sup>2</sup> measurements to attain **< 10 nm spatial resolution** in profiling the AEM-CEM interface
- A long term goal is to develop quantitative spectro-electrochemical approaches for the study of structure and reactivity within **catalyst-membrane architectures**.

## 2. Background

- Bipolar membranes are composed of anion- and cation-exchange phases in adjacent layers (Scheme 1).<sup>3</sup>

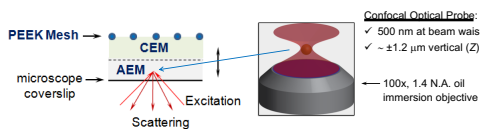
**Scheme 1.** Bipolar membrane under reverse-bias showing water dissociation at the AEM-CEM interface. (See Ref 3 for details.)



- The membranes enable electrochemical devices to operate with the anode and cathode near the pH optimum of the catalytic reactions, providing a route to improved energy efficiency and cost reduction.
- In a reverse-bias configuration, water dissociation at the AEM-CEM interface can replenish H<sup>+</sup> consumed at the cathode (e.g., during H<sub>2</sub> generation) and OH<sup>-</sup> consumed at the anode (e.g., O<sub>2</sub> generation).
- There is interest in a technique to profile the ion-depletion region under bias, and understand the voltage dependence, to guide the development of new membrane materials for improved energy efficiency.

## 3. Experimental

**Confocal Raman Microscopy.** The confocal Raman microscope system is described in Ref. 1. The source was a Kr<sup>+</sup> laser operating at 647.1 nm. A 100x, 1.4 N.A. oil immersion objective brought the laser excitation radiation to a focus within the sample (Scheme 2). Scattered radiation was collected using the same microscope objective. Samples were excited using 3 mW (graphene) or 30 mW (polymer membrane) laser power.



**Scheme 2.** Confocal Raman sampling configuration of bipolar membrane and characteristics of the optical probe.

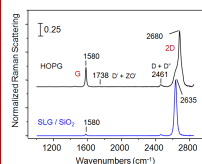
## 3. Experimental (cont.)

**Samples** Bipolar membrane samples (Fumasep FBM) were provided by Nate Lewis (Caltech). The delicate membranes were backed by a PEEK mesh support (Scheme 2). Prior to measurements, the membranes were exchanged in 0.5 M NaCl or 0.1 M NaClO<sub>4</sub>, as indicated. Single layer graphene (SLG) deposited on glass microscope coverslips (SLG/SiO<sub>2</sub>) were provided by Steve Creager (Clemson University).

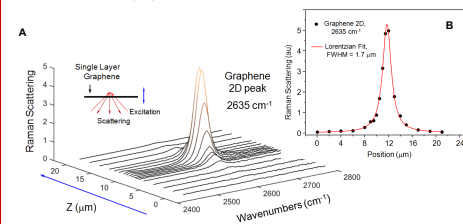
## 4. Results and Discussion:

### A. Confocal Raman Probe Beam Profiling

- To determine spatial resolution limits, it was necessary to measure the intensity profile along the vertical (Z-) axis of the confocal Raman probe beam.
- The profile was measured by stepping through a SLG/SiO<sub>2</sub> interface (Figs 1-2). (See Ref 1 for details)



**Fig. 1.** Raman scattering from highly ordered pyrolytic graphite (HOPG, top) and single layer graphene (SLG) on SiO<sub>2</sub> (bottom) excited at 647.1 nm using 3 mW power. Peak assignments are according to Ref. 4. To aid comparison, each spectrum is normalized to its 2D peak intensity.

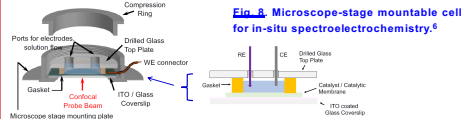


**Fig. 2.** (A) Raman scattering from single layer graphene on SiO<sub>2</sub> (microscope coverslip) recorded as a function of the confocal probe height, Z, relative to the graphene layer. Z = 0 μm is ~12 μm below the coverslip. The peak intensity is maximum when the confocal probe volume central region overlaps the graphene layer. (B) The 2D peak height as a function of Z (points). The red line shows the fit to the Lorentzian function representing the confocal probe Z-dimension profile.<sup>1</sup>

### D. Strategies for In-Situ Characterization

**Confocal Raman microscopy:** A microscope-stage mountable in-situ spectroelectrochemical cell<sup>6</sup> is being tested and adapted (see below).

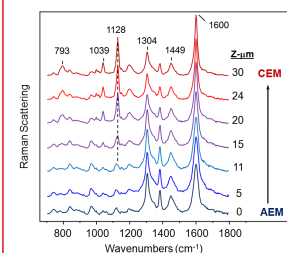
**NR:** NIST capabilities for performing in-situ NR spectro-electrochemistry are being explored (see Panel 7).



**Fig. 3.** Microscope-stage mountable cell for in-situ spectroelectrochemistry.<sup>6</sup>

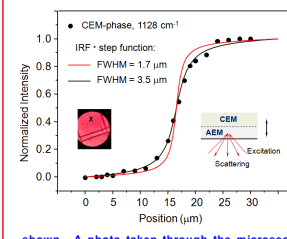
## B. Application to Bipolar Membranes

- Spectra recorded during a confocal Raman depth profile are shown in Fig. 3, while Fig. 4 plots the response of the unique CEM-phase marker.
- The change in CEM-phase marker is slower than the limiting instrument response, indicating a few micron gradient in ionomer composition across the interface.
- FumaTech confirmed a few micron chemical gradient exists at the AEM-CEM interface, due to intentional roughening and addition of a water-splitting catalyst.<sup>5</sup>



**Fig. 3.** Confocal Raman spectra collected at points in the vicinity of the AEM-CEM interface of a Fumasep FBM membrane. Spectra were recorded immediately following ion exchange in 0.5 M NaCl.

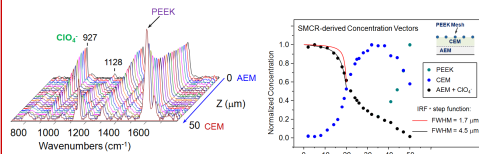
At Z = 0, the confocal probe volume is positioned within the AEM phase and ~15 μm below the AEM-CEM interface. Laser power = 30 mW.



**Fig. 4.** Plot of the unique CEM-phase marker (1128 cm<sup>-1</sup> band) in Figure 3 spectra as a function of measurement position. The solid lines are the convolution of the confocal probe volume Z-profile (IRF) with a step function representing an atomically smooth AEM-CEM junction. Responses for the limiting IRF measured with SLG (red) and IRF derived from fitting the points (black) are shown. A photo taken through the microscope eyepiece is included as an inset and shows the region of beam focus (\*\*) and segment of PEEK mesh.<sup>5</sup>

**Self-modeling curve resolution (SMCR)** applied to a spectral dataset (Fig. 5) associates ClO<sub>4</sub><sup>-</sup> with the AEM-phase (assigns the features to a single pure component).

Traces of ClO<sub>4</sub><sup>-</sup> are detected in the CEM-phase within a few micrometers of the AEM-CEM boundary, consistent with a slight gradient in polymer composition at the interface.

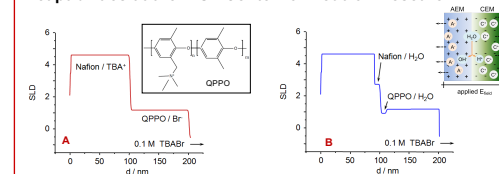


**Fig. 5.** Same as Fig. 3, except membrane was exchanged in 0.1 M NaClO<sub>4</sub> followed by rinsing in DI water for 48 hrs. The ClO<sub>4</sub><sup>-</sup> band (927 cm<sup>-1</sup>) is evident, and PEEK features begin to appear at long distances into the CEM-phase.

**Fig. 6.** Component concentrations derived from SMCR analysis of the Fig. 5 dataset. See Fig. 4 for solid line definitions.

## C. Neutron Reflectometry (NR) Characterization

- Provides ca. 1 nm spatial resolution in depth profiling.<sup>2</sup>
- Strategy:** prepare model AEM-CEM interfaces on NR substrates (e.g., Si) by sequential spin-casting of the AEM and CEM polymers; Use deuterium-labeled mobile tetraalkylammonium ions for contrast enhancement.
- Perform NR using in-situ spectroelectrochemistry capabilities at the NIST-Center for Neutron Research



**Fig. 7.** Calculated scattering length density (SLD) profiles for reflection from a Nafion/QPPO interface (A) without and (B) with an electric field applied.<sup>7</sup>

## 5. Conclusions and Directions:

- Confocal Raman microscopy** enables quantitative **depth-profiling of composition** within layered membrane materials when the instrument response that limits spatial resolution is known; SLG/SiO<sub>2</sub> provides a robust standard for IRF estimation.<sup>1</sup>
- In profiling composition across the bipolar membrane AEM-CEM interface, **spatial resolution** was limited to a few μm but was sufficient to detect the confirmed<sup>5</sup> component variation.
- Ongoing experiments are exploring (1) strategies for in-situ measurements at the AEM-CEM interface and (2) **NR** as a means to attain **nanoscale** (ca. 1 nm) spatial resolution.

## 6. References:

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